

# Search Notes



Application/Control No.

10/763,174

Examiner

Hiep Nguyen

Applicant(s)/Patent under  
Reexamination

TANZAWA ET AL.

Art Unit

2816

## SEARCHED

Class	Subclass	Date	Examiner
327	100	02.09.05	HA
	102	↓	↓
	103	↓	↓
327	349	07.22.05	HA
	347	↓	↓
	348	↓	↓
	361	↓	↓
	363	↓	↓

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST See attachment.	07.21.05	HA